



IN THE UNITED STATES PATENT AND
TRADEMARK OFFICE

PATENT

Applicant(s):	Miguelanez	Atty. Docket No.:	TAI.0800
Serial No.:	10/730,388	Group Art Unit:	2857
Filed:	12/7/2003	Examiner:	NYA
Title:	Methods and Apparatus for Data Analysis		

INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Honorable Commissioner:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §§1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner. A copy of each listed reference (other than U.S. patents and patent publications) is provided as well.

The references are being cited only in the interest of candor and without any admission that they constitute statutory prior art or contain matter which anticipates the invention or which would render the same obvious, either singly or in combination, to a person of ordinary skill in the art.

Inventor: Miguelanez
Serial No.: 10/730,388
Filed: 12/7/2003

This Information Disclosure Statement (IDS) is being filed under 37 C.F.R. §1.97(b)(3), before the mailing of a first Office action on the merits, therefore no fee or statement is required. If there are any questions concerning this IDS, the Examiner is requested to contact the undersigned.

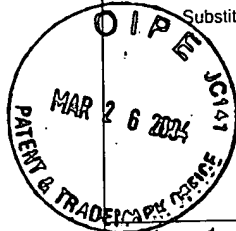
Respectfully submitted,

Date: 23 MAR 2004

By: 
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Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1

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1 of 1 2

Complete if Known

Application Number	10/730,388
Filing Date	12/7/2003
First Named Inventor	Miguelanez
Art Unit	2857
Examiner Name	Not yet assigned
Attorney Docket Number	TAI.0800

U. S. PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
		US-2003/0014205 A1	01/2003	Tabor	
		US-2003/0140287 A1	7/2003	WU et al.	
		US-6,338,148 B1	1/2002	Gillenwater et al.	
		US-6,300,772 B1	10/2001	Brown et al.	
		US-6,279,146	08/2001	Evans et al.	
		US-6,184,048 B1	02/2001	Ramon	
		US-6,182,022	01/2001	Mayle et al.	
		US-5,966,527	10/1999	Krivokapi et al.	
		US-5,956,251 A	9/1999	Atkinson et al.	
		US-5,892,949	04/1999	Noble	
		US-5,835,891 A	11/1998	Stoneking	
		US-5,892,949	04/1999	Noble	
		US-5,694,325	12/1997	Fukuda et al.	
		US-5,539,652	07/1996	Tegethoff	
		US-5,495,417	02/1996	Fukuda et al.	
		US-4,109,511	08/1978	Powers, Jr. et al.	
		US-			
		US-			
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials.	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				
		EP 1067392 A2	06/29/2000	Lejune		
Examiner Signature				Date Considered		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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	Application Number	10/730,388
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	First Named Inventor	Miguelanez
	Art Unit	2857
	Examiner Name	Not yet assigned
Sheet 1 of 2	Attorney Docket Number TAI.0800	

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		"Automatically Analyzing Effects of Process Equipment on Yield", http://www.semiconductor.net/semiconductor/issues/issues/1999/aug99/docs/yield.asp .	
		"Capability Ratios Vary", http://www.qualitydigest.com/june97/html/capablty.html .	
		"Using SPC in Batch Processes" http://www.qualitydigest.com/mar98/html/spcbatch.html .	
		"Splitting Wafer Lots in Semiconductor Manufacturing, Part III: Comparing Two Processes – A Better Approach," http://www.semicondutoronline.com/content/news/article.asp?DocID={66EE75EA-372B-11D4-8C3D-009027DE0829}&Bucket=Features&V	
		"Technique Closes the Loop on Test System Uncertainty," http://www.tmworld.com/articles/05_1999_Technique_Loop.htm .	
		"How Much Measurement Error is Too Much? Part I: Modelling Measurement Data," http://www.testandmeasurement.com/content/news/article.asp?DocID={592878CF-FC4E-11D3-8C2C-009027DE0829}&Bucket=HomeFeaturedArticles .	
		"Data Conductor, Solution for Semiconductor Yield Enhancement"	
		"Predictive Smoothing Algorithm Theory of Operation"	

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